

Stylus profilometer (Bruker DektakXT)



A stylus profilometer is a surface metrology instrument that measures the vertical profile (topography) of a sample by tracing it with a sharp tip (stylus) and recording height changes versus lateral position. It produces 2D line profiles, which can be used to determine step heights (such as coating thickness, etch depth) or surface roughness/waviness parameters.

Our Bruker DektakXT stylus profilometer is equipped with 2 μm -radius stylus with cone angle of 60°.

Overview:

- **Measurement types:** step height, roughness/waviness
- **Scan length:** up to 55 mm
- **Vertical range:** up to 1 mm
- **Stylus force:** 0.03 to 15 mg
- **Max. sample thickness:** 50 mm